

N-Channel Super Junction Power MOSFET III

General Description

The series of devices use advanced trench gate super junction technology and design to provide excellent R_{DS(ON)} with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

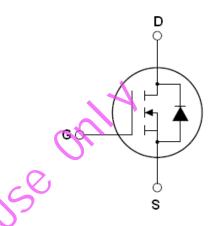
Features

- New technology for high voltage device
- Low on-resistance and low conduction losses
- Small package
- ●Ultra Low Gate Charge cause lower driving requirements
- ●100% Avalanche Tested
- ROHS compliant

Application

- Power factor correction (PFC)
- Switched mode power supplies(SMPS)
- Uninterruptible Power Supply (UPS)

V _{DS}	650	V
R _{DS(ON)TYP}	460	mΩ
I_D	8	A



Schematic diagram

Package Marking And Ordering Information

Device	Device Package	Marking
NCE65T540I	TO-251	NCE65T540I
NCE65T540K	TO-252	NCE65T540K





TO-251

TO-252

Table 1. Absolute Maximum Ratings (T_c=25°C)

Parameter	Symbol	Value	Unit
Drain-Source Voltage (V _{GS} =0V)	V _{DS}	650	V
Gate-Source Voltage (VDS=0V) ,AC (f>1 Hz)	V _G s	±30	V
Continuous Drain Current at Tc=25°C	I _{D (DC)}	8	Α
Continuous Drain Current at Tc=100°C	I _{D (DC)}	5.2	А
Pulsed drain current (Note 1)	I _{DM (pluse)}	32	А
Maximum Power Dissipation(Tc=25℃)	P _D	69	W
Derate above 25°C		0.55	W/°C
Single pulse avalanche energy (Note2)	Eas	156	mJ
Avalanche current ^(Note 1)	I _{AR}	1.7	Α
Repetitive Avalanche energy , t_{AR} limited by T_{jmax} (Note 1)	E _{AR}	0.3	mJ
Parameter	Symbol	Value	Unit



Drain Source voltage slope, V _{DS} ≤480 V,	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS} \le 480 \text{ V,I}_{SD} < I_D$	dv/dt	15	V/ns
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55+150	°C

Table 2. Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R _{thJC}	1.81	°C /W
Thermal Resistance, Junction-to-Ambient (Maximum)	R _{thJA}	62	°C /W

Table 3. Electrical Characteristics (TA=25℃unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
On/off states			4	, ,,		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	650			V
Zero Gate Voltage Drain Current(Tc=25°C)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			1	μA
Zero Gate Voltage Drain Current(Tc=125℃)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			100	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V			±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} ,I _D =250μA	3		4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =4A		460	540	mΩ
Dynamic Characteristics		0,0				
Input Capacitance	C _{Iss}	V -50V/V -0V		590		pF
Output Capacitance	Coss	V_{DS} =50V, V_{GS} =0V, F=1.0MHz		37		pF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVID2		0.9		pF
Total Gate Charge	Q_g	\/ -400\/ L -0A		14.6	22	nC
Gate-Source Charge	Q_{gs}	V _{DS} =480V,I _D =8A, V _{GS} =10V		4		nC
Gate-Drain Charge	Q_{gd}			6.7		nC
Switching times						
Turn-on Delay Time	t _{d(on)}			8		nS
Turn-on Rise Time	t _r	V_{DD} =380V, I_{D} =4A,		6		nS
Turn-Off Delay Time	t _{d(off)}	$R_G=4.7\Omega, V_{GS}=10V$		59	75	nS
Turn-Off Fall Time	t _f			10	15	nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}	T -25°C			8	Α
Pulsed Source-drain current(Body Diode)	I _{SDM}	T _C =25°C			32	Α
Forward On Voltage	V _{SD}	Tj=25°C,I _{SD} =8A,V _{GS} =0V		0.9	1.2	V
Reverse Recovery Time	t _{rr}			230		nS
Reverse Recovery Charge	Q _{rr}	Tj=25°C,I _F =4A,di/dt=100A/µs		1.2		uC
Peak Reverse Recovery Current	I _{rrm}			10.5		Α

Notes: 1.Repetitive Rating: Pulse width limited by maximum junction temperature

^{2.} Tj=25°C,VDD=50V,VG=10V, R_G=25 Ω





TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure 1. Safe operating area

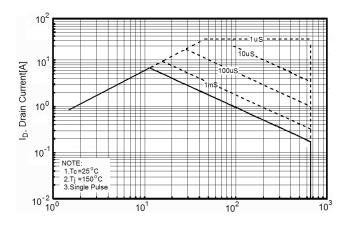


Figure 3. Source-Drain Diode Forward Voltage

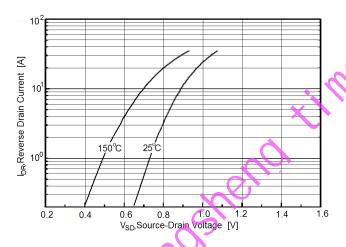


Figure 5. Transfer characteristics

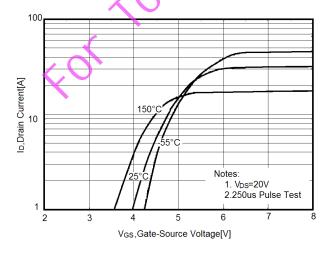


Figure 7. R_{DS(ON)} vs Junction Temperature

Figure 2. Transient Thermal Impedance

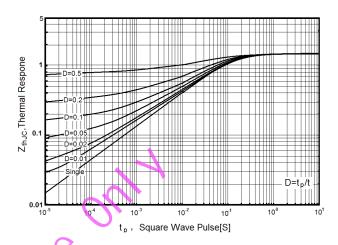


Figure4. Output characteristics

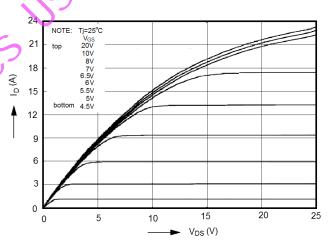


Figure 6. Static drain-source on resistance

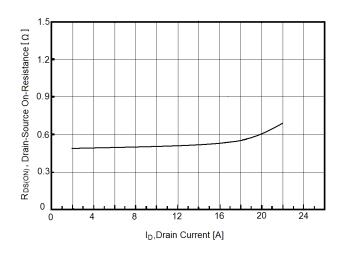
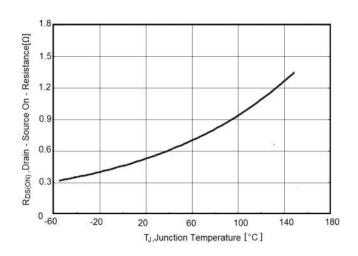


Figure 8. BV_{DSS} vs Junction Temperature





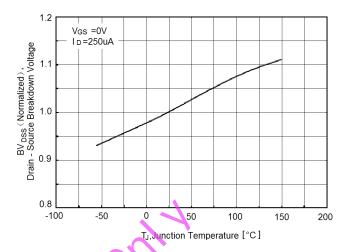


Figure 9. Maximum I_D vs Junction Temperature

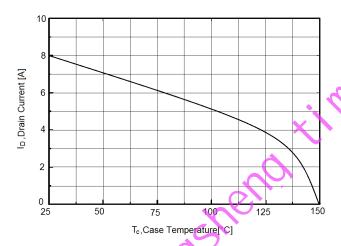


Figure10. Capacitance

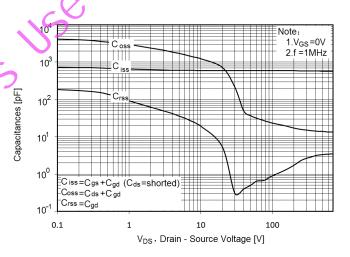
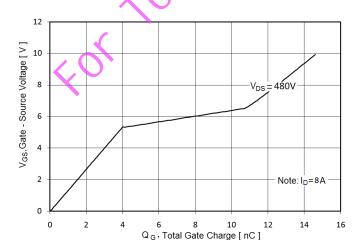


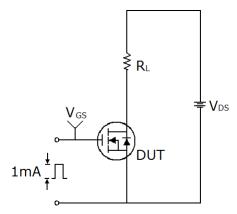
Figure 11. Gate charge waveforms

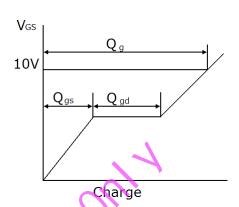




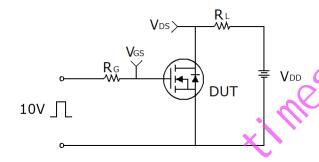
Test circuit

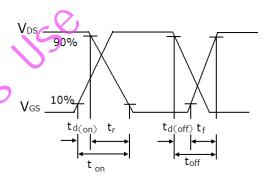
1) Gate charge test circuit & Waveform



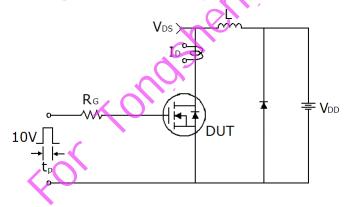


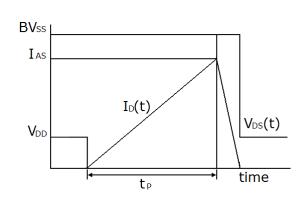
2) Switch Time Test Circuit:





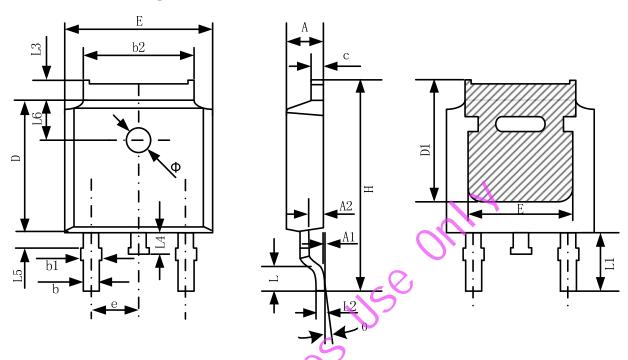
3) Unclamped Inductive Switching Test Circuit & Waveforms







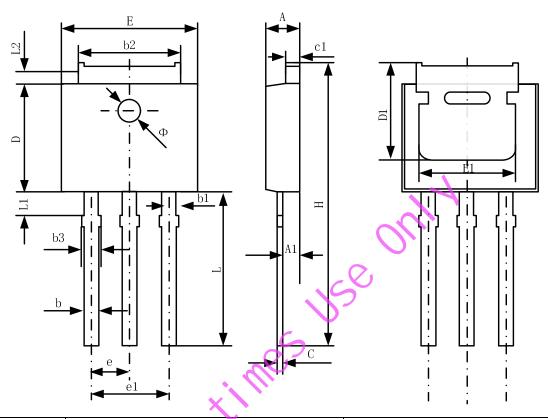
TO-252-2 Package Information



Symbol	Dimensions I	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	2.20	2.38	0.087	0.094	
A1	0.00	0.10	0.000	0.004	
A2	0.90	1.10	0.035	0.043	
b	0.72	0.85	0.028	0.033	
b1	0.72	0.90	0.028	0.035	
b2	5.13	5.46	0.202	0.215	
С	0.47	0.60	0.019	0.024	
D	6.00	6.20	0.236	0.244	
D1	5.25		0.207	1	
E	6.50	6.70	0.256	0.264	
E1	4.70		0.185		
e	2.19	2.39	0.086	0.094	
Н	9.80	10.40	0.386	0.409	
L	1.40	1.70	0.055	0.067	
L1	2.90	REF	0.114 REF		
L2	0.508	BSC	0.020 BSC		
L3	0.90	1.25	0.035	0.049	
L4	0.60	1.00	0.024	0.039	
L5	0.15	0.75	0.006	0.030	
L6	1.80 REF		0.071 REF		
Ф	1.20	1.40	0.047	0.055	
θ	0°	8°	0°	8°	



TO-251 Package Information



Symbol	Dimensions I	n Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	2.20	2.35	0.087	0.093	
A1	0.90	1.10	0.035	0.043	
b	0.56	0.69	0.022	0.027	
b1	0.77	0.90	0.030	0.035	
b2	5.23	5.43	0.206	0.214	
b3		1.05	0.000	0.041	
С	0.46	0.59	0.018	0.023	
c1	0.46	0.59	0.018	0.023	
₹ ₽	6.00	6.20	0.236	0.244	
D1	5.20		0.205		
Е	6.50	6.70	0.256	0.264	
E1	4.60	5.00	0.181		
e	2.24	2.34	0.088	0.092	
e1	4.47	4.67	0.176	0.184	
Н	16.18	16.78	0.637	0.661	
L	9.00	9.60	0.354	0.378	
L1	0.95	1.35	0.037	0.053	
L2	0.90	1.25	0.035	0.049	



ATTENTION:

- Any and all NCE products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your NCE representative nearest you before using any NCE products described or contained herein in such applications.
- NCE assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all NCE products described or contained herein.
- Specifications of any and all NCE products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- NCE Power Semiconductor CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all NCE products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of NCE Power Semiconductor CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. NCE believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the NCE product that you intend to use.
- This catalog provides information as of Mar. 2010. Specifications and information herein are subject to change without notice.

ox Loud